



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Schneegans, et al. Docket No.: 2001 P 17353 US
Serial No.: 10/826,954 Art Unit: 2829
Filed: April 15, 2004 Examiner: Nguyen, Jimmy
Title: Probe Needle for Testing Semiconductor Chips and Method for Producing Said
Probe Needle

Mail Stop: Amendment
Commissioner for Patents
P. O. Box 1450
Alexandria, VA 22313-1450

SUPPLEMENTAL AMENDMENT

Dear Sir:

The following amendments and remarks are presented as a supplement to Applicant's
Amendment filed March 7, 2005. Please amend the above-referenced application as follows.